

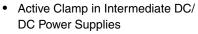
## HM4487-VB Datasheet P-Channel 100-V (D-S) MOSFET

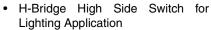
PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)			
- 100	0.160 at V <sub>GS</sub> = - 10 V	- 2.5 <sup>c</sup>	23.2 nC			
- 100	0.200 at V <sub>GS</sub> = - 4.5 V	- 2.3 <sup>c</sup>	23.2 110			

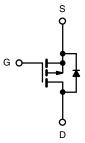
# APPLICATIONS • Active Clamp in In

Trench Power MOSFET
 100% R<sub>q</sub> and UIS Tested

**FEATURES** 







P-Channel MOSFET

			1	
S	1	]	8	D
S	2		7	D
S	3		6	D
G	4		5	D
			J	

**SO-8** 

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	- 100	.,		
Gate-Source Voltage		V <sub>GS</sub>	± 20	V	
	T <sub>C</sub> = 25 °C		- 2.5		
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C		- 2.3		
Continuous Diain Current (1) = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 2 <sup>a, b</sup>		
	T <sub>A</sub> = 70 °C		- 1.6 <sup>a, b</sup>	^	
Pulsed Drain Current	I <sub>DM</sub>	- 15	A		
Continuous Courses Brain Binds Coursest	T <sub>C</sub> = 25 °C		- 4.9		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	- 2.5 <sup>a, b</sup>		
Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	- 15		
Single-Pulse Avalanche Energy	L=0.1 IIII	E <sub>AS</sub>	11.25	mJ	
	T <sub>C</sub> = 25 °C		5.9		
Maximum Daylar Dissination	T <sub>C</sub> = 70 °C		3.8	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>a, b</sup>	VV	
	T <sub>A</sub> = 70 °C		2 <sup>a, b</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

#### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Based on  $T_C$  = 25 °C.

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, b</sup>	t ≤ 10 s	R <sub>thJA</sub>	33	40	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R <sub>thJF</sub>	17	21	C/VV	

#### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. Maximum under steady state conditions is 80  $^{\circ}\text{C/W}.$



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				•			
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 100			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 165			
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η = - 250 μΑ		- 6.6		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zava Cata Valtaga Dvain Curvant	I	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V			- 1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10	μΑ	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 8			Α	
	D	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 2 A		0.160		0	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5V, I <sub>D</sub> = - 1.5 A		0.200		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = 2 A		12		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			1190			
Output Capacitance	C <sub>oss</sub>	$V_{DS} = -50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		61		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			42			
Tatal Oata Obarra	Qg	$V_{DS} = -50 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -2 \text{ A}$		27.5	42		
Total Gate Charge				23.2	35	~0	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = -50 \text{ V}, V_{GS} = -6 \text{ V}, I_{D} = -2 \text{ A}$		5.4		nC	
Gate-Drain Charge	Q <sub>gd</sub>			8.4			
Gate Resistance	$R_g$	f = 1 MHz		6.1	9.2	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			20	30		
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 75 V, $R_L$ = 25 $\Omega$		95	145		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong -3 \text{ A}, V_{GEN} = -6 \text{ V}, R_g = 1 \Omega$		38	60		
Fall Time	t <sub>f</sub>			34	51	no	
Turn-On Delay Time	t <sub>d(on)</sub>			11	18	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 75 V, $R_L$ = 25 $\Omega$		28	42		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \cong$ - 2 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		52	78		
Fall Time	t <sub>f</sub>			35	53		
<b>Drain-Source Body Diode Characterist</b>	ics						
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 13	۸	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 15	Α	
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 2 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			65	90	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = - 4 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		180	270	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	i <sub>F</sub> = -4 A, αί/αι = 100 A/μs, 1 <sub>J</sub> = 25 °C		45			
Reverse Recovery Rise Time	t <sub>b</sub>	t <sub>b</sub>		20		ns	

#### Notes:

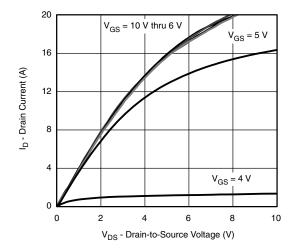
2

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

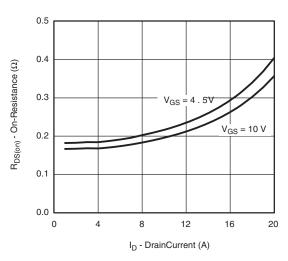
a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$ 

b. Guaranteed by design, not subject to production testing.

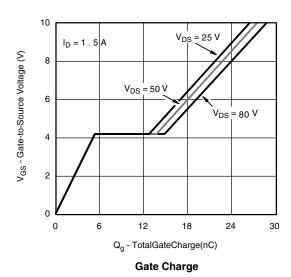


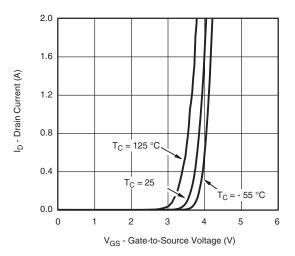


### **Output Characteristics**

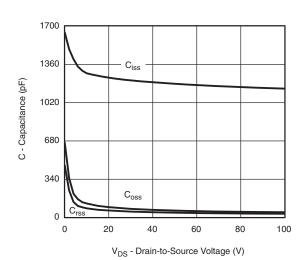


#### On-Resistance vs. Drain Current and Gate Voltage

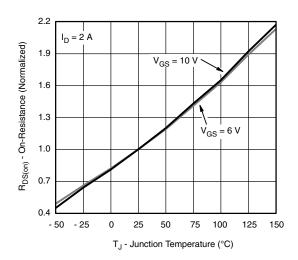




**Transfer Characteristics** 

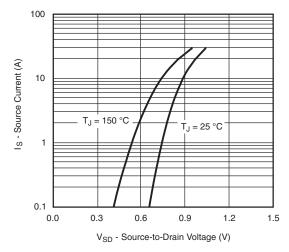


Capacitance

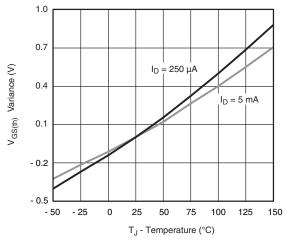


On-Resistance vs. Junction Temperature

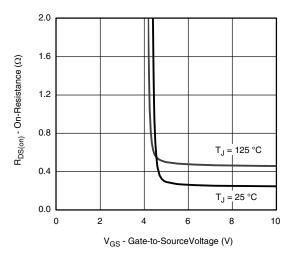




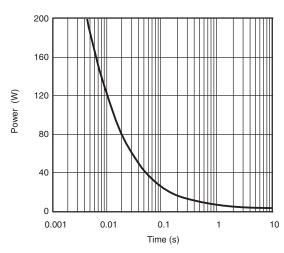
#### Source-Drain Diode Forward Voltage



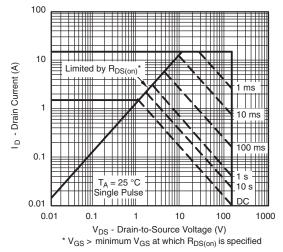
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage

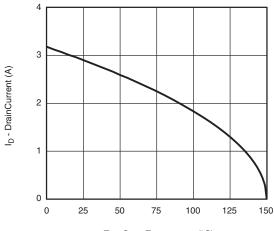


Single Pulse Power, Junction-to-Ambient



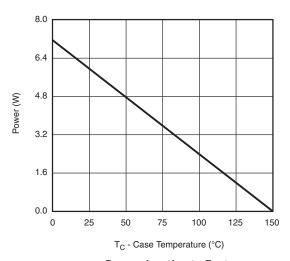
Safe Operating Area, Junction-to-Ambient



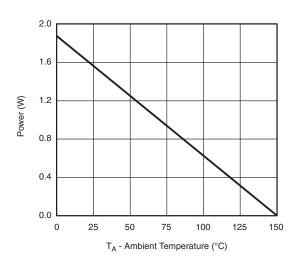


T<sub>C</sub> - Case Temperature (°C)

#### **Current Derating\***



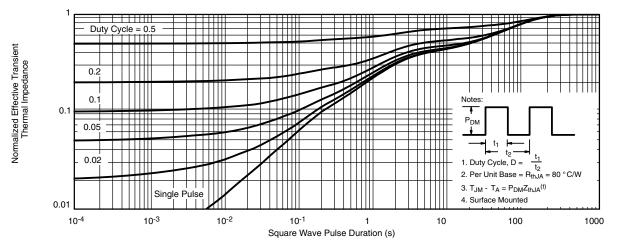




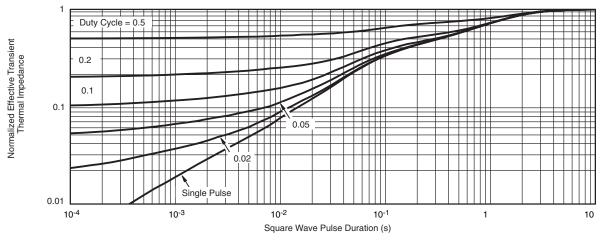
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





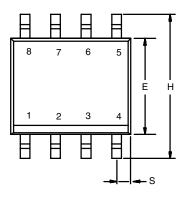
Normalized Thermal Transient Impedance, Junction-to-Ambient

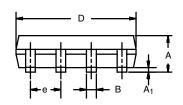


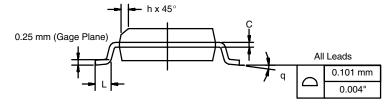
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







	MILLIMETERS		INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FON C 00507 Per 1 44 Con 00					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



## **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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